

Notice of References Cited	Application/Control No. 10/733,845	Applicant(s)/Patent Under Reexamination ANDREWS ET AL.	
	Examiner Evan Pert	Art Unit 2829	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	B	US-6,211,488	04-2001	Hoekstra et al.	219/121.72
	C	US-5,543,365	08-1996	Wills et al.	438/462
	D	US-5,185,295	02-1993	Goto et al.	438/463
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	Lizotte, "Laser Dicing of Chip Scale and Silicon Wafer Scale Packages", July 2003, Electronics Manufacturing Technology Symposium, pages 1-5.
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.